TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VCXR162652FT

Low-Voltage 16-Bit Bus Transceiver/Register with 3.6-V Tolerant Inputs and Outputs

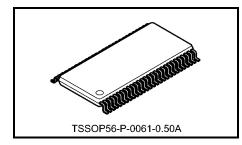
The TC74VCXR162652FT is a high-performance CMOS 16-bit bus transceiver/register. Designed for use in 1.8-V, 2.5-V or 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

It is also designed with overvoltage tolerant inputs and outputs up to $3.6\ V.$

This device is bus transceiver with 3-state outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the internal registers.

The $26-\Omega$ series resistor helps reducing output overshoot and undershoot without external resistor.

All inputs are equipped with protection circuits against static discharge.



Weight: 0.25 g (typ.)

Features (Note)

- 26-Ω series resistors on outputs
- Low-voltage operation: V_{CC} = 1.8 to 3.6 V
- High-speed operation: $t_{pd} = 3.8 \text{ ns (max)} (V_{CC} = 3.0 \text{ to } 3.6 \text{ V})$

 $t_{pd} = 4.9 \text{ ns (max) (VCC} = 2.3 \text{ to } 2.7 \text{ V)}$

 $t_{pd} = 9.8 \text{ ns (max) (VCC} = 1.8 \text{ V)}$

• Output current: IOH/IOL = ±12 mA (min) (VCC = 3.0 V)

 $: I_{OH}/I_{OL} = \pm 8 \text{ mA (min) (V}_{CC} = 2.3 \text{ V)}$

: $I_{OH}/I_{OL} = \pm 4$ mA (min) ($V_{CC} = 1.8$ V)

- Latch-up performance: -300 mA
- ESD performance: Machine model $\geq \pm 200 \text{ V}$

Human body model ≥ ±2000 V

- · Package: TSSOP
- Bidirectional interface between 2.5 V and 3.3 V signals.
- 3.6-V tolerant function and power-down protection provided on all inputs and outputs

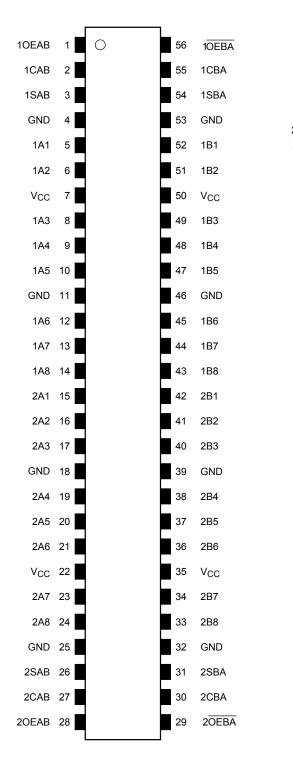
Note: Do not apply a signal to any bus pins when it is in the output mode. Damage may result.

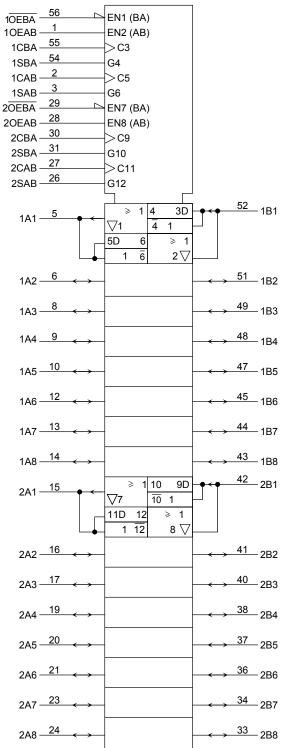
All floating (high impedance) bus pins must have their input level fixed by means of pull-up or pull-down resistors.

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Pin Assignment (top view)

IEC Logic Symbol





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Truth Table

		Contro	I Inputs			В	us	Function					
OEAB	OEBA	CAB	CBA	SAB	SBA	Α	В	Function					
		X*	X*	Х	Х	Input	Input	The output functions of A and B Busses are					
L	Н	Λ	^	^	^	Z	Z	disabled.					
L	П	4		Х	х	Х	х	Both A and B Busses are used as inputs to the internal flip-flops. Data on the Bus will be stored on the rising edge of the Clock.					
						Input	Output						
		X*	X*	L	Х	L	L	The data on the A bus are displayed on the B bus.					
						Н	Н						
		_	X*	L	X	L	L	The data on the A bus are displayed on the B Bus, and are stored into the A storage					
Н	Н		^	_	^	Н	н	flip-flops on the rising edge of CAB.					
		X*	X*	Н	х	х	Qn	The data in the A storage flop-flops are displayed on the B Bus.					
		_					L	The data on the A Bus are stored into the A					
			X*	Н	Х	Н	Н	storage flip-flops on the rising edge of CAB, and the stored data propagate directly onto the B Bus.					
						Output	Input						
		X*	X*	Х	X	Χ	Χ	X L		L	L	L	The data on the B Bus are displayed on the A bus.
						н н							
		X*	_	X	L	L	L	The data on the B Bus are displayed on the A Bus, and are stored into the B storage					
L	L	^.		^	_	Н	Н	flip-flops on the rising edge of CBA.					
		X*	X*	х	Н	Qn	х	The data in the B storage flip-flops are displayed on the A Bus.					
			_			L	L	The data on the B Bus are stored into the B storage flip-flops on the rising edge of CBA.					
		X*		X	Н	н	н	and the stored data propagate directly onto the A Bus.					
						Output	Output						
Н	L X* X*		н	Н	Qn	Qn	The data in the A storage flop-flops are displayed on the B Bus, and the data in the B storage flop-flops are displayed on the A.						

X: Don't care

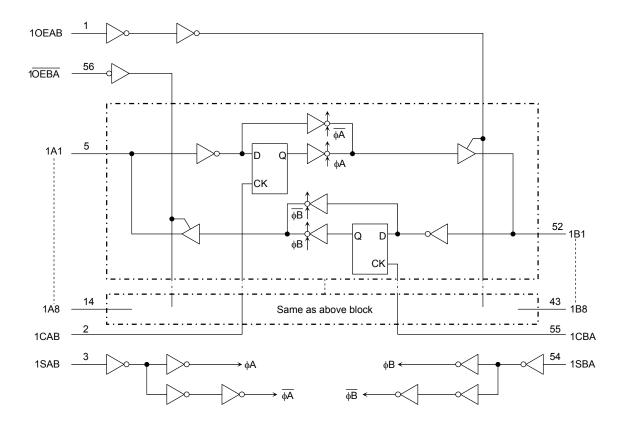
Z: High impedance

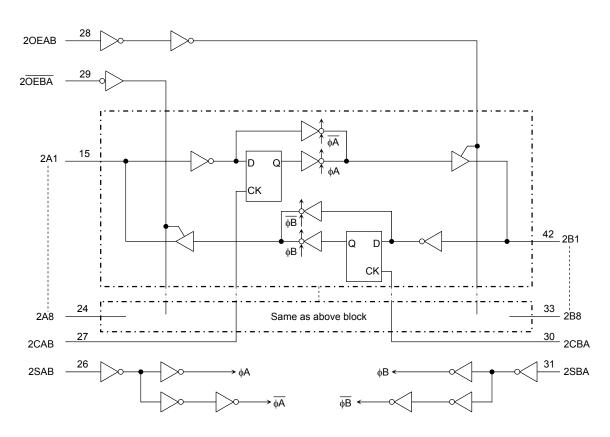
Qn: The data stored into the internal flip-flops by most recent low to high transition of the clock inputs.

*: The clocks are not internally gated with either OEAB or $\overline{\text{OEBA}}$.

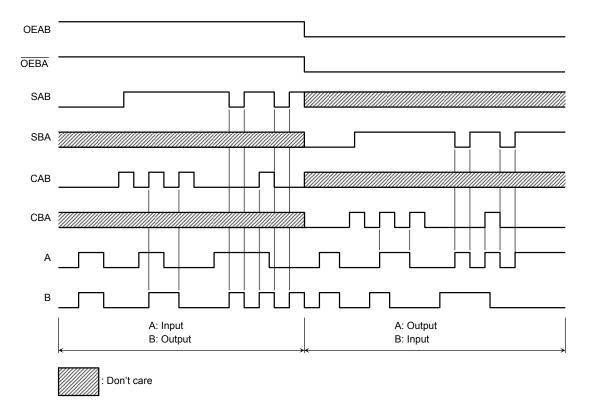
Therefore, data on the A and/or B busses may be clocked into the storage flip-flops at any time.

System Diagram





Timing Chart





Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	−0.5 to 4.6	V
DC input voltage (CAB, CBA, SAB, SBA, OEAB, OEBA)	V _{IN}	-0.5 to 4.6	V
		-0.5 to 4.6 (Note 2)	
DC bus I/O voltage	V _{I/O}	-0.5 to V_{CC} + 0.5	V
		(Note 3)	
Input diode current	I _{IK}	-50	mA
Output diode current	lok	±50 (Note 4)	mA
DC output current	lout	±50	mA
Power dissipation	P _D	400	mW
DC V _{CC} /ground current per supply pin	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: OFF state

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4: Vout < GND, Vout > Vcc

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V _{CC}	1.8 to 3.6	V	
Tower supply voltage	VCC	1.2 to 3.6 (Note 2)	V	
Input voltage (CAB, CBA, SAB, SBA, OEAB, OEBA)	V _{IN}	-0.3 to 3.6	V	
Bus I/O voltage	V _{I/O}	0 to 3.6 (Note 3)	V	
Bus 1/O voltage	v I/O	0 to V _{CC} (Note 4)	V	
		±12 (Note 5)		
Output current	I _{OH} /I _{OL}	±8 (Note 6)	mA	
		±4 (Note 7)		
Operating temperature	T _{opr}	-40 to 85	°C	
Input rise and fall time	dt/dv	0 to 10 (Note 8)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: OFF state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \text{ to } 3.6 \text{ V}$

Note 6: $V_{CC} = 2.3 \text{ to } 2.7 \text{ V}$

Note 7: $V_{CC} = 1.8 \text{ V}$

Note 8: $V_{IN} = 0.8$ to 2.0 V, $V_{CC} = 3.0$ V



Electrical Characteristics

DC Characteristics (Ta = -40 to 85°C, 2.7 V < $V_{CC} \le 3.6$ V)

Characteristics		Symbol	Test (Condition		Min	Max	Unit
		.,		1001 001.001				0
Input voltage	H-level	V _{IH}		_	2.7 to 3.6	2.0	_	V
input voltage	L-level	V _{IL}		_	2.7 to 3.6	_	0.8	V
				$I_{OH} = -100 \mu A$	2.7 to 3.6	V _{CC} - 0.2	_	
	H-level	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -6 \text{ mA}$	2.7	2.2	_	
				$I_{OH} = -8 \text{ mA}$	3.0	2.4	_	
Output voltage				$I_{OH} = -12 \text{ mA}$	3.0	2.2	_	V
		V _{OL}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OL} = 100 μA	2.7 to 3.6	_	0.2	
	L-level			I _{OL} = 6 mA	2.7	_	0.4	
	L-level			I _{OL} = 8 mA	3.0	_	0.55	
				I _{OL} = 12 mA	3.0	_	8.0	
Input leakage curr	ent	I _{IN}	V _{IN} = 0 to 3.6 V		2.7 to 3.6	_	±5.0	μА
2 state sutaut OF	C atata aureant		$V_{IN} = V_{IH}$ or V_{IL}		2-1-22		±10.0	^
3-state output OFF state current		loz	$V_{OUT} = 0$ to 3.6 V		2.7 to 3.6		±10.0	μΑ
Power-off leakage current		l _{OFF}	V_{IN} , $V_{OUT} = 0$ to 3.6 V	/	0	_	10.0	μΑ
Quiescent supply current		loo	V _{IN} = V _{CC} or GND		2.7 to 3.6		20.0	_
Quiescent supply	Current	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le 3.6 \text{ V}$		2.7 to 3.6	_	±20.0	μΑ
Increase in I _{CC} pe	er input	Δlcc	V _{IH} = V _{CC} - 0.6 V		2.7 to 3.6	_	750	

DC Characteristics (Ta = -40 to 85°C, 2.3 V \leq V_{CC} \leq 2.7 V)

Characteristics		Symbol	Symbol Test Condition			Min	Max	Unit
		Cymbol			V _{CC} (V)	IVIIII		Offic
Input voltage	H-level	V _{IH}		_	2.3 to 2.7	1.6	_	V
input voitage	L-level	VIL		_	2.3 to 2.7	_	0.7	V
				I _{OH} = -100 μA	2.3 to 2.7	V _{CC} - 0.2		
	H-level	Voh	V _{IN} = V _{IH} or V _{IL}	$I_{OH} = -4 \text{ mA}$	2.3	2.0	_	
				$I_{OH} = -6 \text{ mA}$	2.3	1.8	_	٧
Output voltage				$I_{OH} = -8 \text{ mA}$	2.3	1.7	_	
				I _{OL} = 100 μA	2.3 to 2.7	_	0.2	
	L-level	V _{OL}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OL} = 6 mA	2.3	_	0.4	
				I _{OL} = 8 mA	2.3	_	0.6	
Input leakage curre	ent	I _{IN}	V _{IN} = 0 to 3.6 V		2.3 to 2.7	_	±5.0	μΑ
3-state output OFF state current		loz	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 3.6 \text{ V}$		2.3 to 2.7	_	±10.0	μΑ
Power-off leakage current		l _{OFF}	V _{IN} , V _{OUT} = 0 to 3.6 V		0	_	10.0	μΑ
Outgoont oursts	urront		V _{IN} = V _{CC} or GND		2.3 to 2.7	_	20.0	^
Quiescent supply of	unent	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le 3.6 \text{ V}$		2.3 to 2.7	_	±20.0	μΑ



DC Characteristics (Ta = -40 to 85°C, 1.8 V \leq V $_{CC}$ < 2.3 V)

Characteristics S		Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
Input voltage	H-level	V _{IH}	_	_	1.8 to 2.3	0.7 × V _{CC}	_	V
input voltage	L-level	V _{IL}	_	_	1.8 to 2.3	_	0.2 × V _{CC}	V
	H-level	V _{OH}	V _{IN} = V _{IH} or V _{II}	$I_{OH} = -100 \mu A$	1.8	V _{CC} - 0.2	_	
Output voltage		0		I _{OH} = -4 mA	1.8	1.4	_	V
	L-level	V _{OL}	V _{IN} = V _{IH} or V _{II}	$I_{OL} = 100 \mu A$	1.8	_	0.2	
			VIN - VIH OI VIL	$I_{OL} = 4 \text{ mA}$	1.8	_	0.3	
Input leakage currer	nt	I _{IN}	V _{IN} = 0 to 3.6 V		1.8		±5.0	μΑ
3-state output OFF state current		loz	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 3.6 \text{ V}$		1.8	_	±10.0	μА
Power-off leakage current		I _{OFF}	V _{IN} , V _{OUT} = 0 to 3.6 V		0	_	10.0	μΑ
Ouise sent supply support		Icc	V _{IN} = V _{CC} or GND		1.8	_	20.0	μА
Quicocint supply co	Quiescent supply current		$V_{CC} \le (V_{IN}, V_{OUT}) \le 3.6 \text{ V}$		1.8		±20.0	μΛ



AC Characteristics (Ta = –40 to 85°C, input: t_{r} = t_{f} = 2.0 ns, C_{L} = 30 pF, R_{L} = 500 Ω) (Note 1)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
			1.8	100	_	
Maximum clock frequency	f _{max}	Figure 1, Figure 3	2.5 ± 0.2	200	_	MHz
			3.3 ± 0.3	250		
			1.8	1.5	9.8	
Propagation delay time	t _{pLH}	Figure 1, Figure 2	2.5 ± 0.2	0.8	4.9	ns
(An, Bn-Bn, An)	tpHL		3.3 ± 0.3	0.6	3.8	
			1.8	1.5	9.8	
Propagation delay time	t _{pLH}	Figure 1, Figure 3	2.5 ± 0.2	0.8	5.8	ns
(CAB, CBA-Bn, An)	tpHL		3.3 ± 0.3	0.6	4.1	
Drawagation delay time			1.8	1.5	9.8	
Propagation delay time	t _{pLH}	Figure 1, Figure 2	2.5 ± 0.2	0.8	5.8	ns
(SAB, SBA-Bn, An)	tpHL		3.3 ± 0.3	0.6	4.4	
Output anable time		Figure 1, Figure 4, Figure 5	1.8	1.5	9.8	
Output enable time (OEAB, OEBA -An, Bn)	t _{pZL}		2.5 ± 0.2	8.0	5.9	ns
(OLAB, OLBA-AII, BII)	t _{pZH}		3.3 ± 0.3	0.6	4.3	
Output disable time	t	Figure 1, Figure 4, Figure 5	1.8	1.5	9.4	ns
(OEAB, OEBA -An, Bn)	t _{pLZ}		2.5 ± 0.2	8.0	5.2	
(OEAB, OEBA -AII, BII)	tpHZ		3.3 ± 0.3	0.6	4.5	
	4		1.8	4.0	_	
Minimum pulse width	tw (H)	Figure 1, Figure 3	2.5 ± 0.2	1.5	_	ns
	t _{w (L)}		3.3 ± 0.3	1.5	_	
			1.8	2.5	_	
Minimum setup time	ts	Figure 1, Figure 3	2.5 ± 0.2	1.5		ns
			3.3 ± 0.3	1.5		
			1.8	1.0	_	
Minimum hold time	t _h	Figure 1, Figure 3	2.5 ± 0.2	1.0	_	ns
			3.3 ± 0.3	1.0		
	t _{osLH}		1.8	_	0.5	
Output to output skew	tosHL	(Note 2)	2.5 ± 0.2	_	0.5	ns
	USTIL		3.3 ± 0.3	_	0.5	

Note 1: For $C_L = 50 \ pF$, add approximately 300 ps to the AC maximum specification.

Note 2: Parameter guaranteed by design. $(t_{OSLH} = |t_{pLHm} - t_{pLHn}|, \, t_{OSHL} = |t_{pHLm} - t_{pHLn}|)$



Dynamic Switching Characteristics

(Ta = 25°C, input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500$ Ω)

Characteristics	Symbol	Test Condition			Unit
Characteristics	Cymbol	rest contaition	V _{CC} (V)	Тур.	o i i
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 1.8	0.15	
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 2.5	0.25	V
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 3.3	0.35	
	V _{OLV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note	1.8	-0.15	
Quiet output minimum dynamic V _{OI}		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 2.5	-0.25	V
,		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 3.3	-0.35	
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 1.8	1.55	
Quiet output minimum dynamic V _{OH}	V _{OHV}	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note) 2.5	2.05	V
,		V _{IH} = 3.3 V, V _{IL} = 0 V (Note) 3.3	2.65	

Note: Parameter guaranteed by design.

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}	(OEAB, OEBA, CAB, CBA, SAB, SBA)	1.8, 2.5, 3.3	6	pF
Bus I/O capacitance	C _{I/O}	An, Bn	1.8, 2.5, 3.3	7	pF
Power dissipation capacitance	C _{PD}	$f_{\text{IN}} = 10 \text{ MHz}$ (Note)	1.8, 2.5, 3.3	20	pF

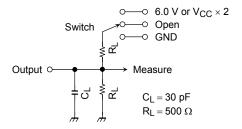
Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/16 \text{ (per bit)}$



AC Test Circuit



Parameter	Switch		
t _{pLH} , t _{pHL}	Open		
t _{pLZ} , t _{pZL}	6.0 V V _{CC} × 2	$@V_{CC} = 3.3 \pm 0.3 \text{ V} \\ @V_{CC} = 2.5 \pm 0.2 \text{ V} \\ @V_{CC} = 1.8 \text{ V} \\ \\$	
t _{pHZ} , t _{pZH}	GND		

Figure 1

AC Waveform

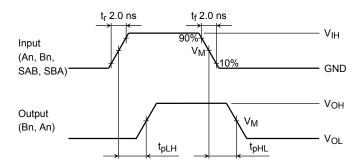


Figure 2 t_{pLH}, t_{pHL}

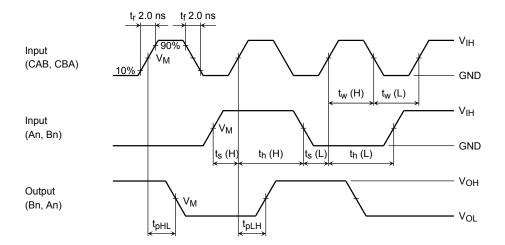


Figure 3 t_{pLH} , t_{pHL} , t_{w} , t_{s} , t_{h}

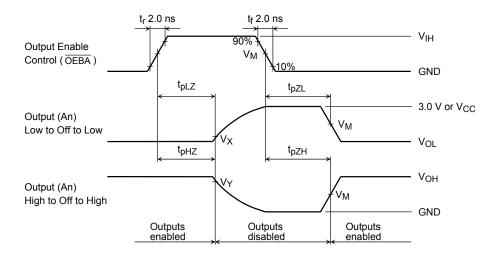


Figure 4 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

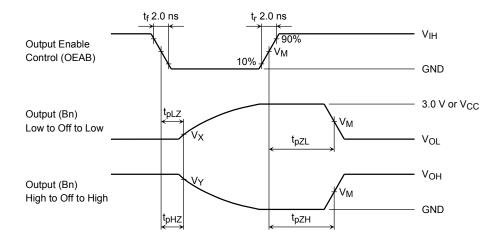
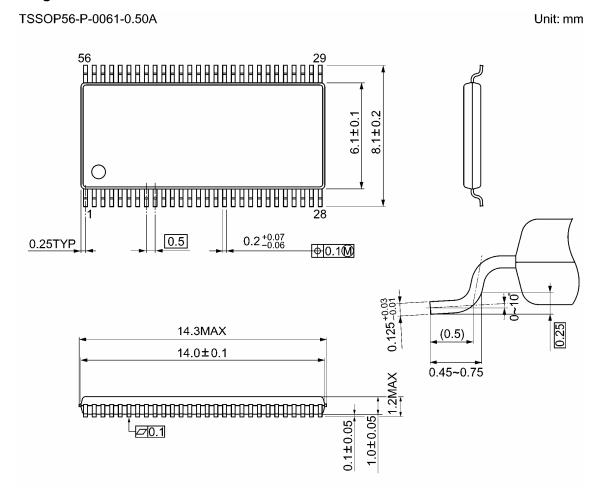


Figure 5 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

Symbol	V _{CC}							
Symbol	$3.3\pm0.3~\text{V}$	$2.5\pm0.2\textrm{V}$	1.8 V					
VIH	2.7 V	V _{CC}	V _{CC}					
V_{M}	1.5 V	V _{CC} /2	V _{CC} /2					
VX	V _{OL} + 0.3 V	V _{OL} + 0.15 V	V _{OL} + 0.15 V					
VY	V _{OH} – 0.3 V	V _{OH} – 0.15 V	V _{OH} – 0.15 V					

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Package Dimensions



Weight: 0.25 g (typ.)

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20070701-EN GENERAL

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